

ABCs, Antimonide Based Compound Semiconductors

- ▶ *High speed, low power, electronics, terahertz sources*

Christie Marrian
Microsystems Technology Office



Key Personnel

- ❖ Contracting Officer's Representatives
 - Colin Wood, ONR
 - Cindy Hanson, SPAWAR
 - Don Mullin, SPAWAR
 - Gernot Pomrenke, AFOSR
- ❖ DARPA Team
 - Julia Edwards, BAH
 - Courtney Brown, BAH
- ❖ Contractor PIs
 -
 - Barry Gilbert, Erik Daniel, Mayo
 - Suzanne Mohney, PSU
- ❖ DARPA PMs

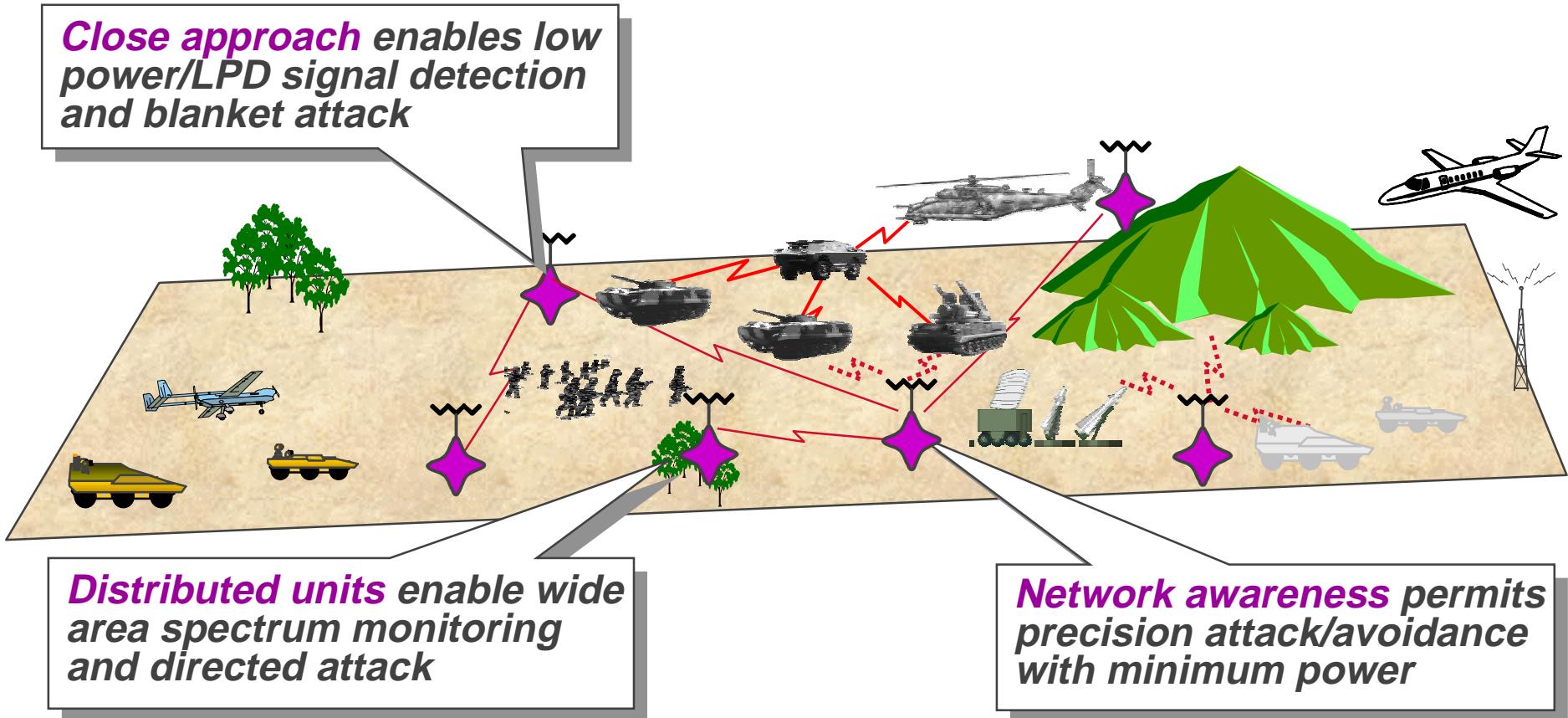


WolfPack Phase II/III



**Dr. Paul Kolodzy
WolfPack PM**

WolfPack : Operational Concept



WolfPack Technology responds to advanced LPD/LPI, Packet Network Radios

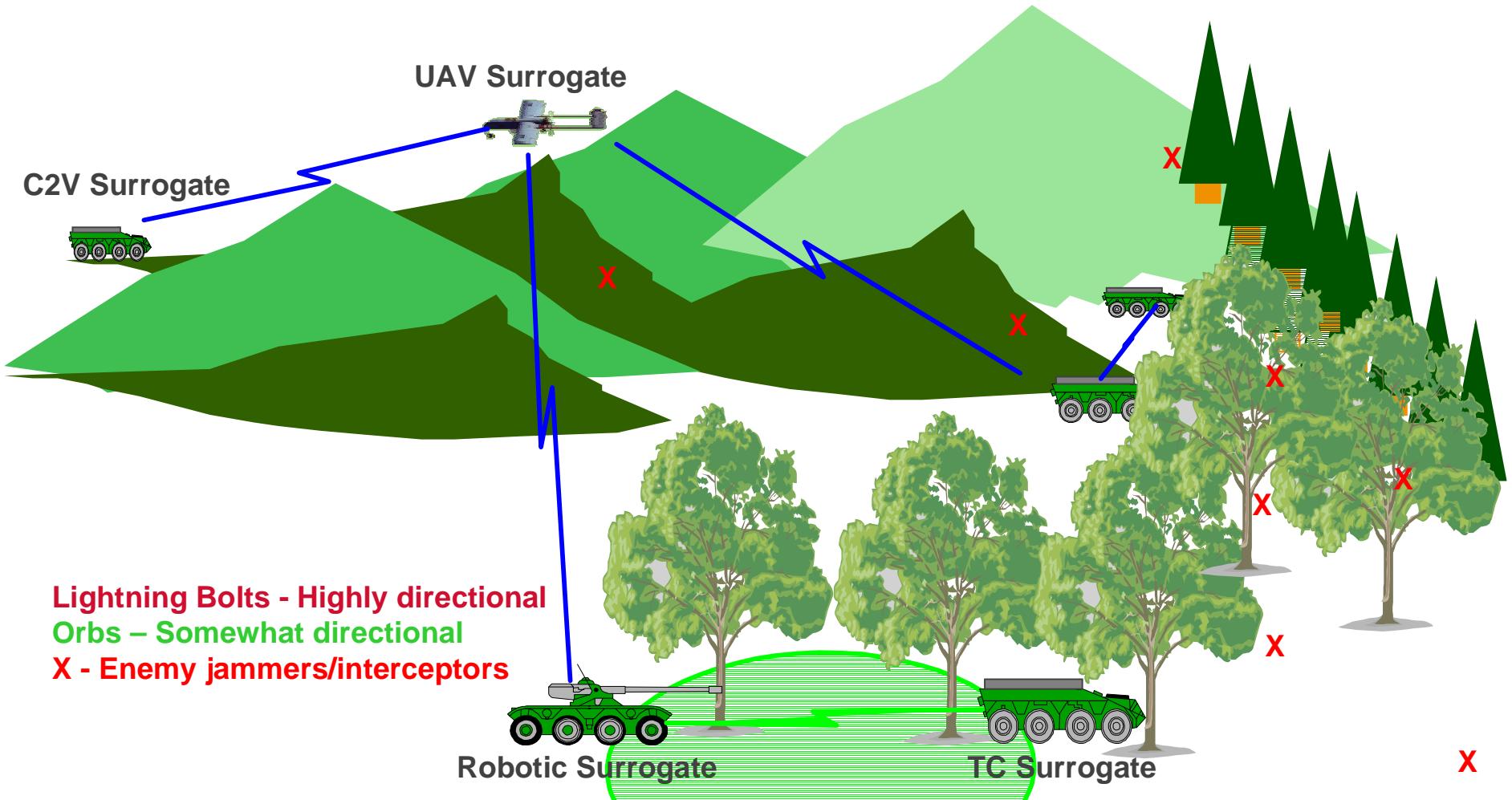


DARPA
Future Combat Systems
Communications

25 June 2001

Dr. James A. Freebersyser
Program Manager, DARPA/ATO
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DARPA FCS-C: Demo



Demonstrate Notional FCS Cell at TRL-5 for PDR by 15 Apr 03
Show Scaling Across Multiple FCS Cells in Simulation by 15 Aug 03

FCS Communications Limiters

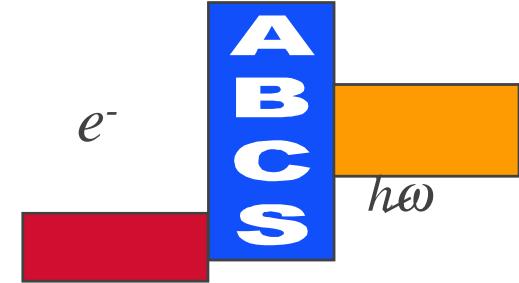
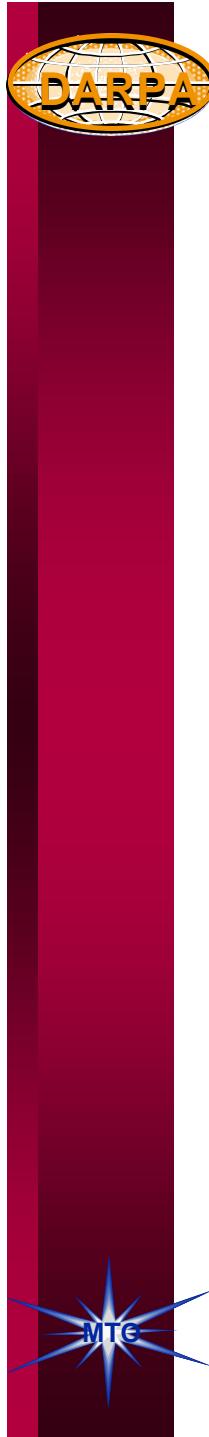
Poor Assumption

- ❖ There Will Be Sufficient Always On Bandwidth to Support All Users
 - Intel, SA, C2, sensors, robotics, etc.

Three Factors That Will Limit Network-Centric Operations

- ❖ Electronic Attack
 - The bad guy will NOT sit idly by; the bad guy will attack the network
 - Detection, interception, jamming, denial of service, etc.
- ❖ LOS and Foliage Constraints for Dispersed Operations
 - For disbursed operations, multiple UAVs may be required per FCS cell
- ❖ Available Spectrum Is Being Reduced as Demand Increases
 - Exploit higher frequencies (eventually including optical)

Potentially, Each Factor Reduces Bandwidth Available by 10x (1000x Total)

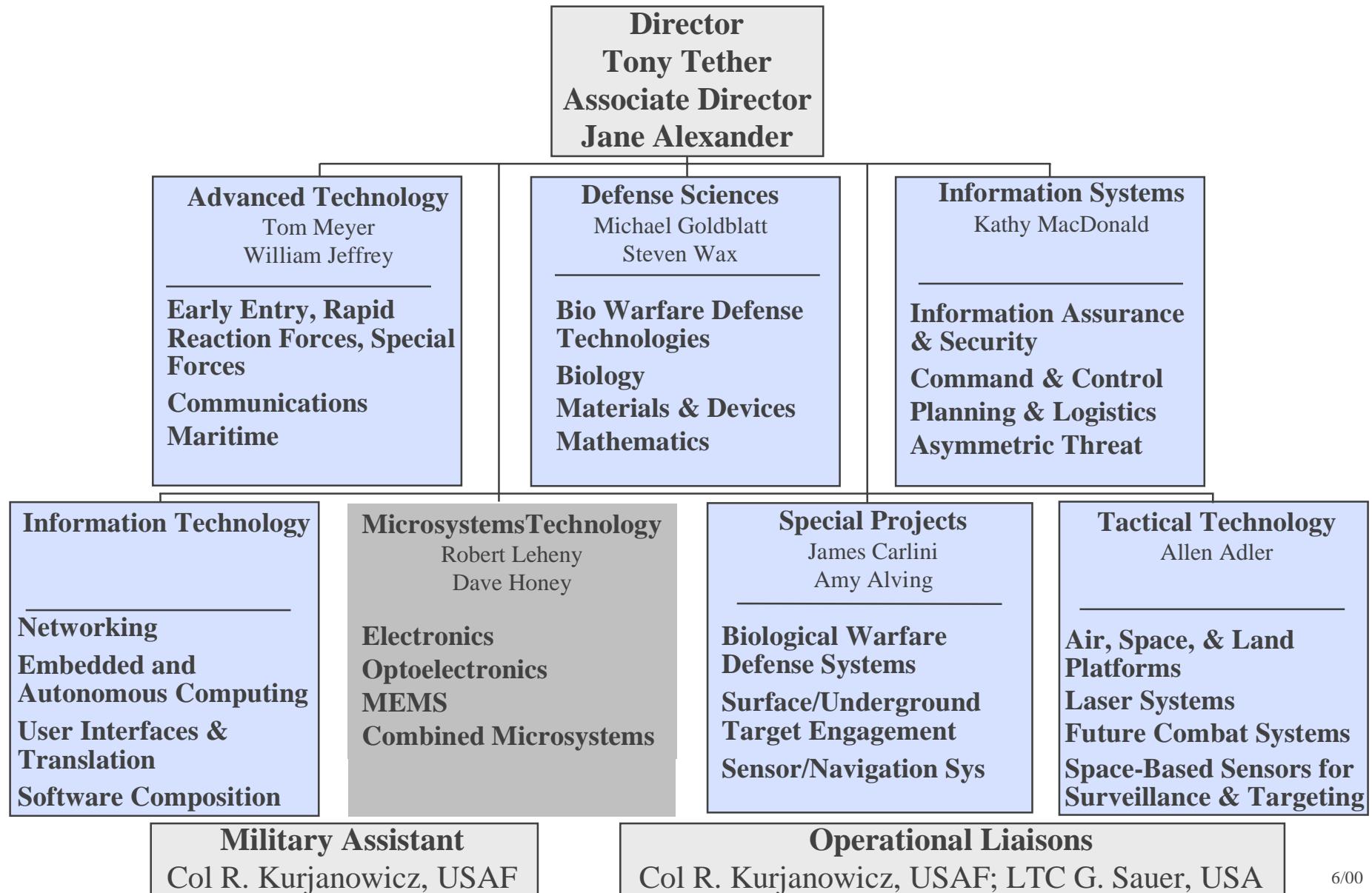


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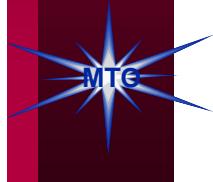
DARPA Organization

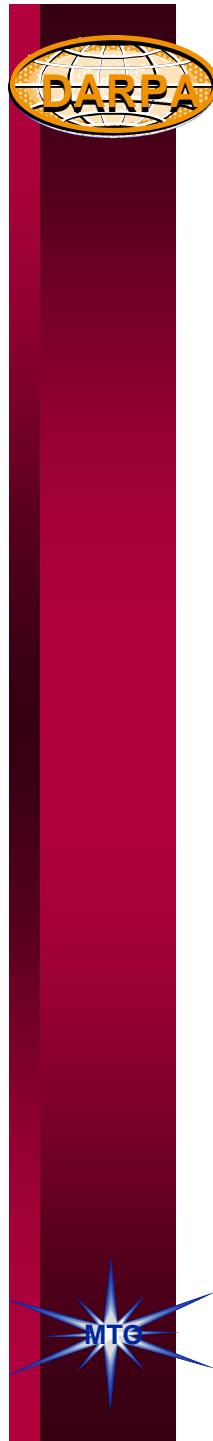




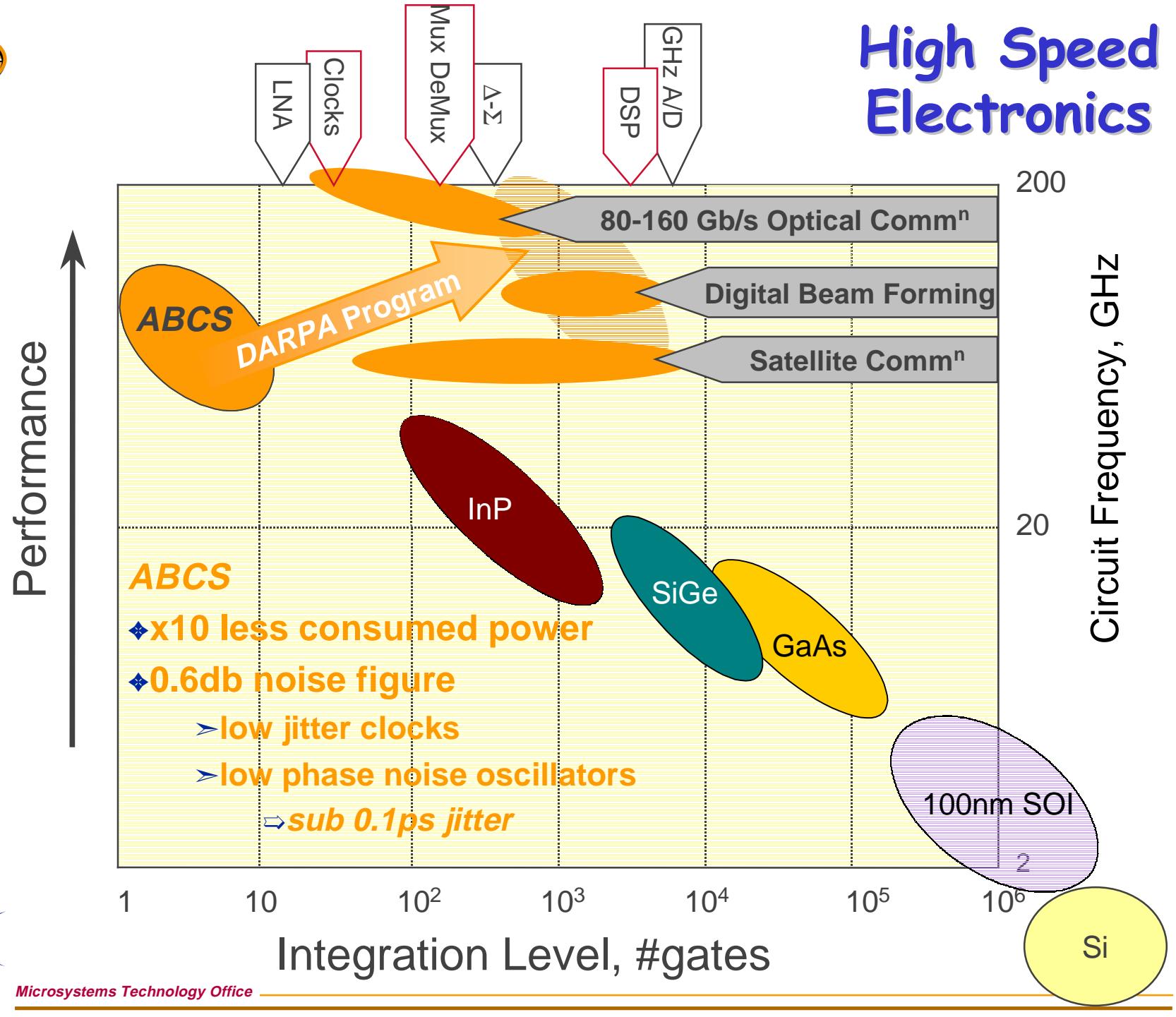
MTO & Microelectronics

- ❖ Scaling Si Microelectronics
 - How 'Nano' can we go?
 - Mixed signal Si based Microsystems
 - TEAM
 - Heterogeneous integration
 - IRFFE
- ❖ Alternative Material Systems
 - Molecular Electronics
 - Devices, Assembly and Architecture
 - **ABCS family of Compound Semiconductors**
 - High speed, Low consumed power
 -



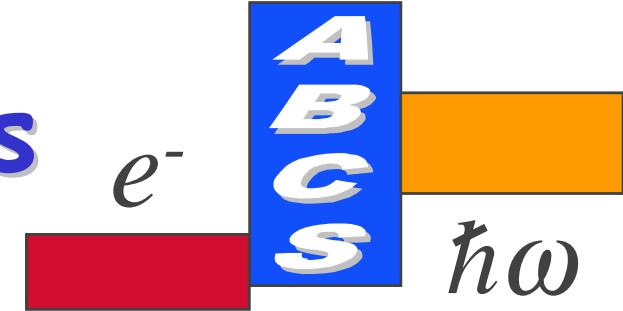


High Speed Electronics

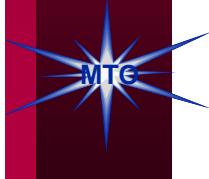




ABCs Program Goals

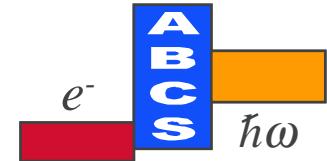


- ❖ Low consumed power, high frequency electronics circuits based on the 6.1 Angstrom family of compound semiconductors (ABCs).
 - *Substrate Technology.* ABCS substrates with $<<10^8$ defects/cm² with essentially any desired thermal and/or electronic property
 - *Electronics Integration.* $>5\times10^3$ devices/circuit through demonstrations of analog, digital or mixed signal circuits which have beyond state-of-the-art performance in terms of frequency of operation and low power consumption
 - *THz to IR Devices:* Innovative devices that operate in the THz to the IR region of the electromagnetic spectrum

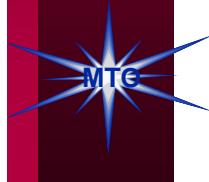


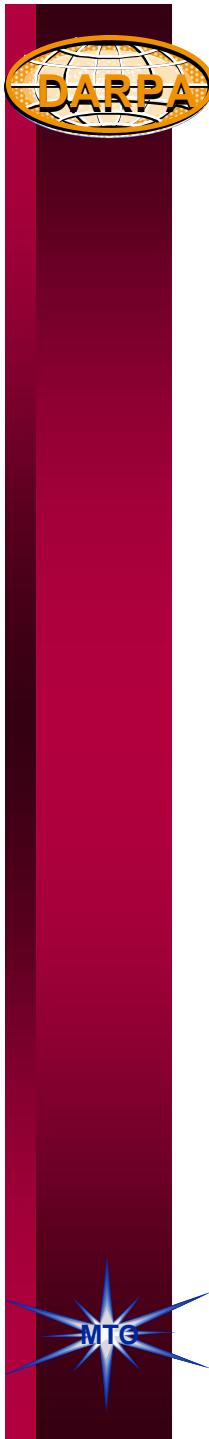


Programmatic Challenges

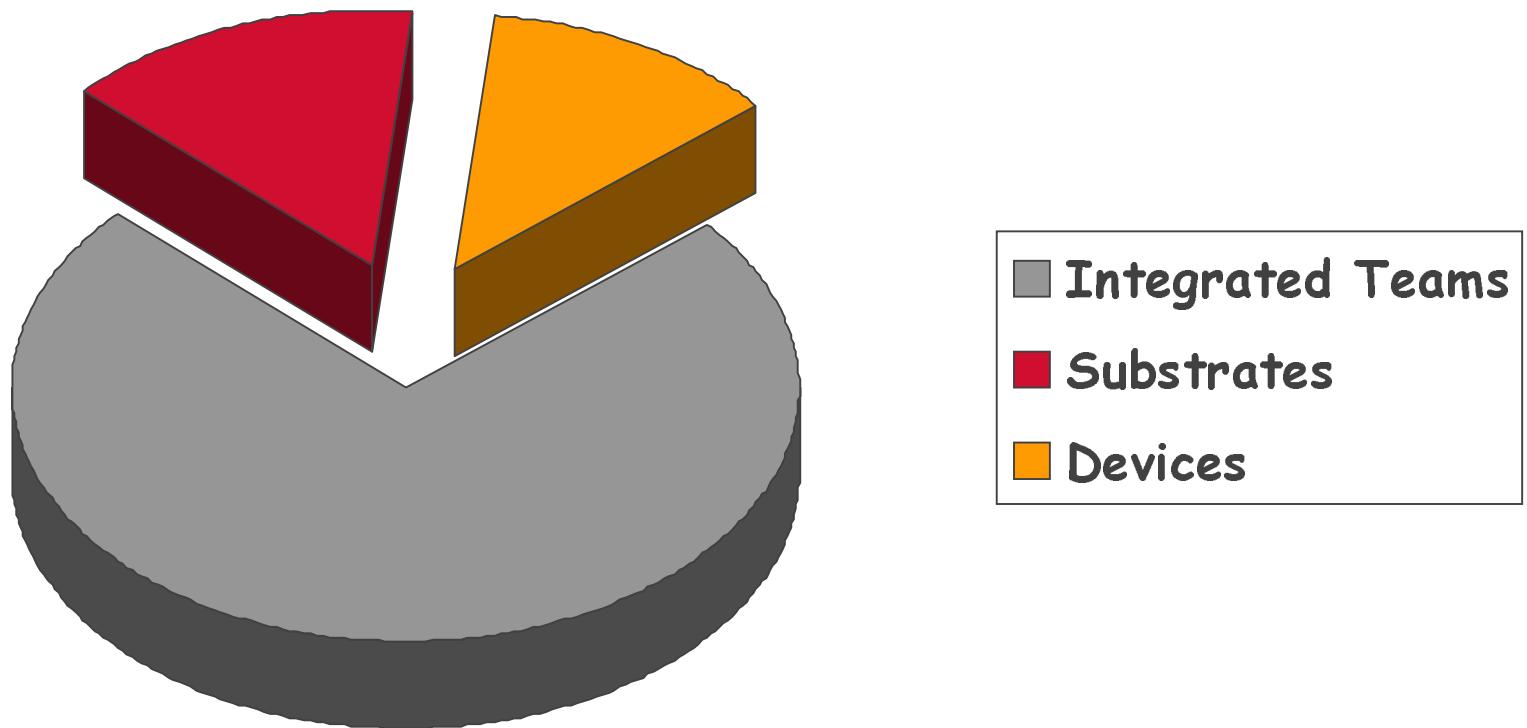


Task	Challenge	Program Approach
Substrates	Low defect, $<10^8/\text{cm}^2$, semi-insulating substrates Availability	◆ Lateral overgrowth and bond & etch back ◆ Contract substrate deliverables
Low Power, High Speed Electronics	Expanding beyond single transistors Design for 100GHz & low consumed power	◆ Develop process technology to integrate 1000's devices ◆ Teaming: model-design-layout-fab-evaluate
Exit Strategy	Defining ABCS program goals	◆ Milestones driven by projected system needs ◆ 'Customers' involved in evaluation of milestones





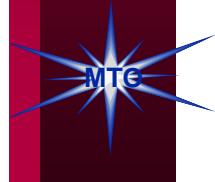
Resource Allocation





ABCS Contractors

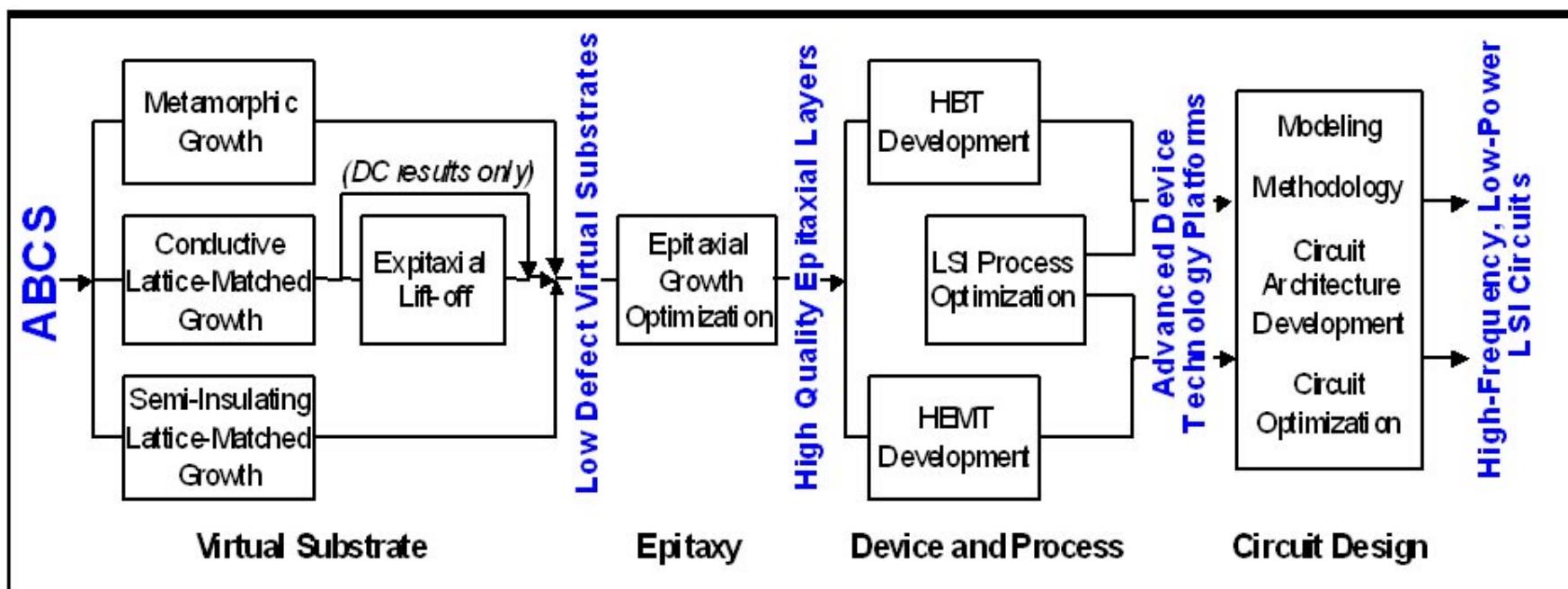
Organization	Project Title
HRL	Antimonide-Based Compound Semiconductor (ABCS)
TRW/NRL	Antimonide-Based Compound Semiconductors (ABCS)
Rockwell/USCB	Antimonide-Based Compound Semiconductor Transferred-Substrate Transistors and Circuits
Lowell/AFRL	Low Defect Density Substrates and High Quality Epi-Substrate Interfaces for ABCS
Columbia	InAs HVT for Extremely Low Power and High Speed Applications
PSU	Contacts to Antimonide-Based Compound Semiconductors
Rice	Antimonide-Based Semiconductor Quantum Wells for Coherent Terahertz Wave Generation
NRL	ABCS IR Sources
Mayo	Mayo SPPDG Collaborative Role in the ABCS Program



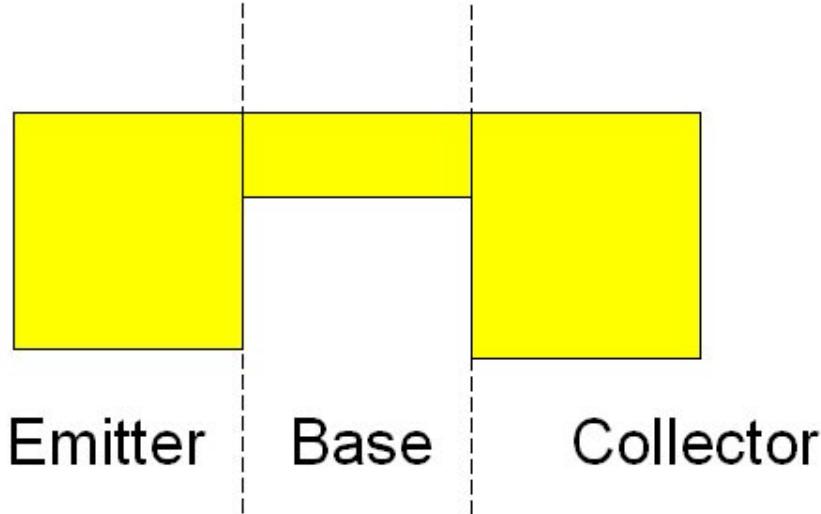
TRW Team's Technical Plan

TRW

TRW team's technology development flow efficiently addresses the technical issues of 6.1 Å development

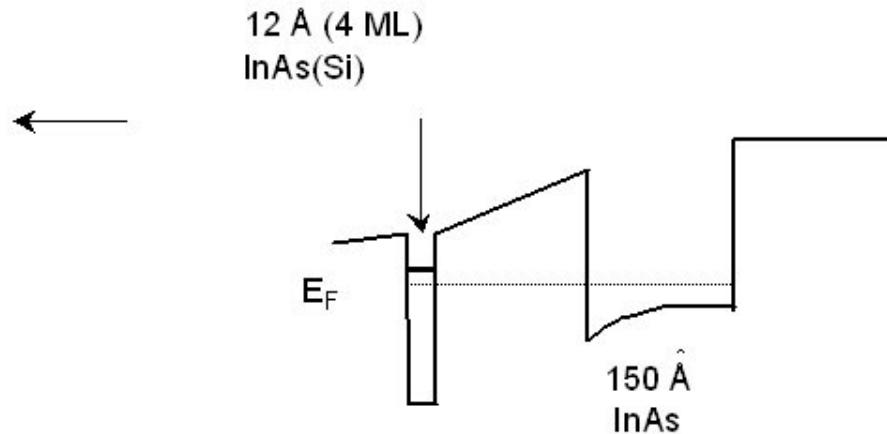


Ideal HBT



- ▶ The beauty of 6.1A system is the wide variety of materials to design “ideal” semiconductor devices.

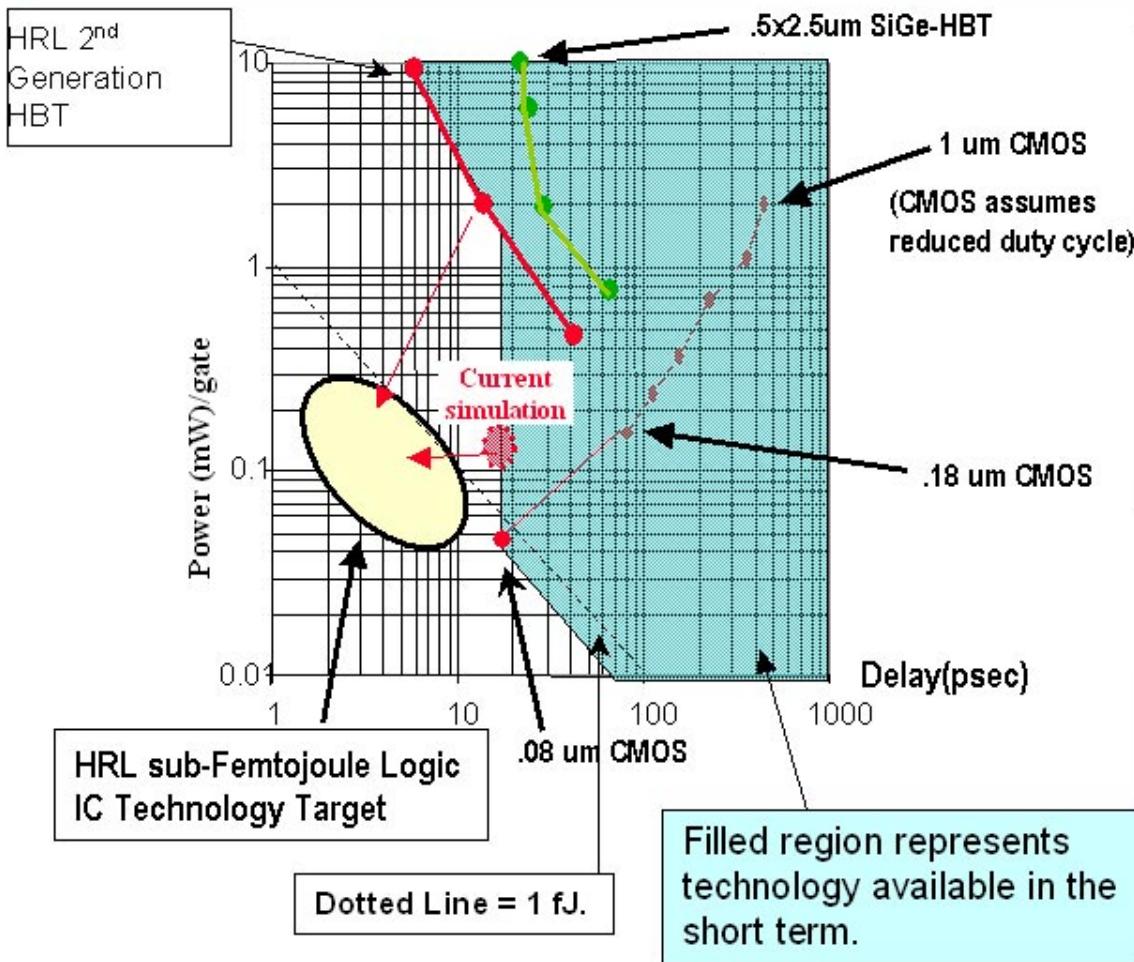
InAs 20 Å
AlSb 100 Å
InAs 3 Å
InAs(Si) 9 Å
AlSb 125 Å
InAs 150 Å
AlSb 2.4 μm
GaAs 0.3 μm
Si GaAs substrate



$$n_s = 2.5 \times 10^{12} \text{ cm}^{-2}, \mu = 17,000 \text{ cm}^2/\text{Vsec}$$

- ▶ Used Si doping in a thin (12 Å) InAs donor layer located above the InAs quantum well to achieve high sheet carrier density.
- ▶ The large confinement energy of the thin quantum well allows the electrons to transfer into the 150 Å InAs channel.
- ▶ Sheet densities as high as $3.2 \times 10^{12} \text{ cm}^{-2}$ and $5.6 \times 10^{12} \text{ cm}^{-2}$ have been achieved by single- and double-sided modulation doping, respectively.

Moving towards Higher-Speed and Lower-Power ICs.



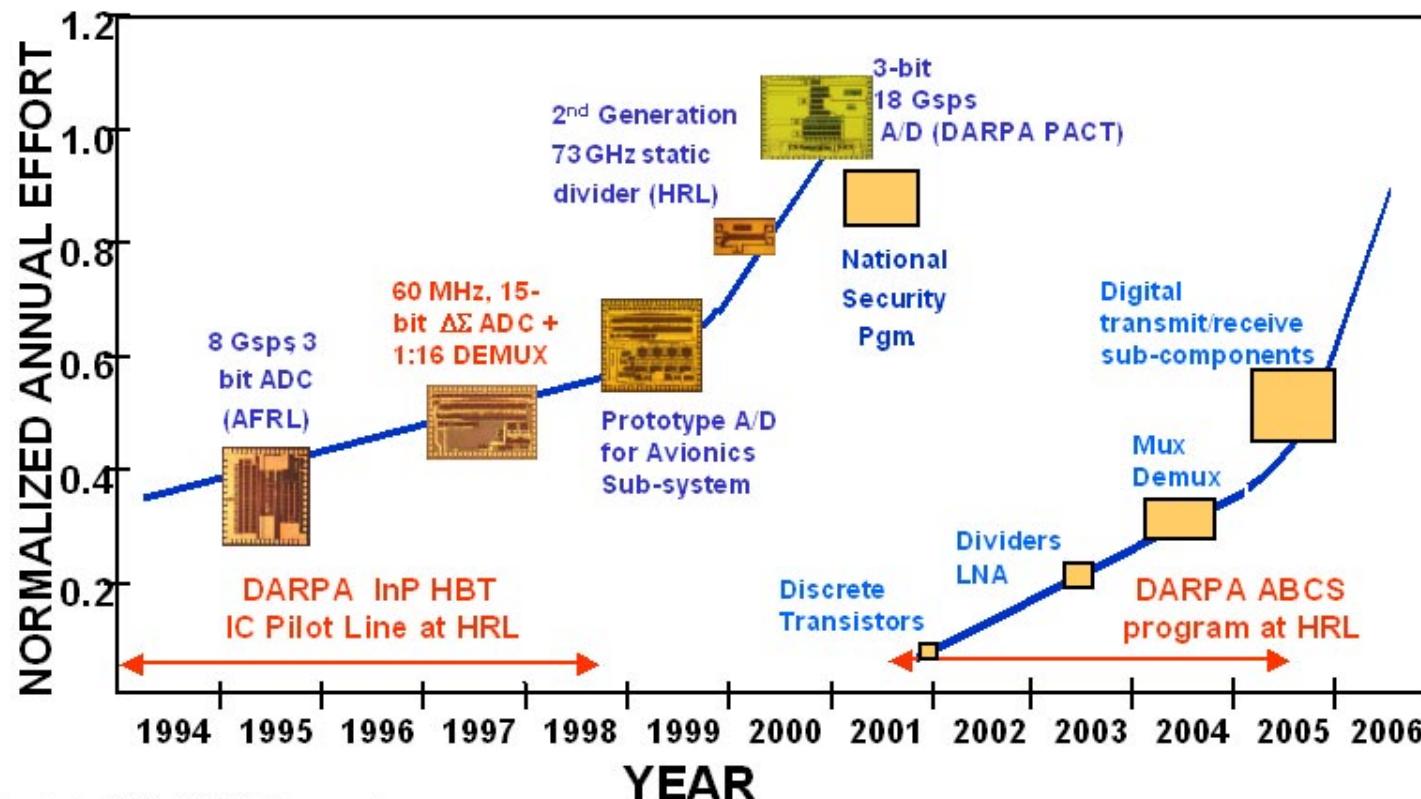
Systems are becoming:

- More mobile (i.e. battery powered).
- More complex (digitally beam-steered phased arrays).
- More demanding (higher bandwidth, mmW frequencies, all digital).

Future systems will need more speed with a large reduction in power-delay.

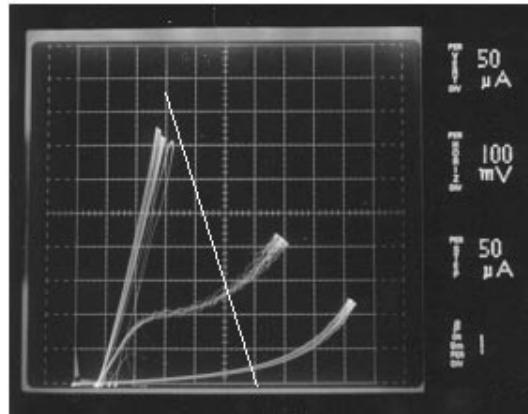
HRL Model for ABCS Application Insertion Based on InP Experience

- ABCS insertions expected to follow a similar model to InP, but with a shorter development and insertion cycle.
- Uses include integrated sub-components for digital transmit/receive at Ka, Q and possibly V-bands.
- Applications include digital beam-forming for phased arrays.

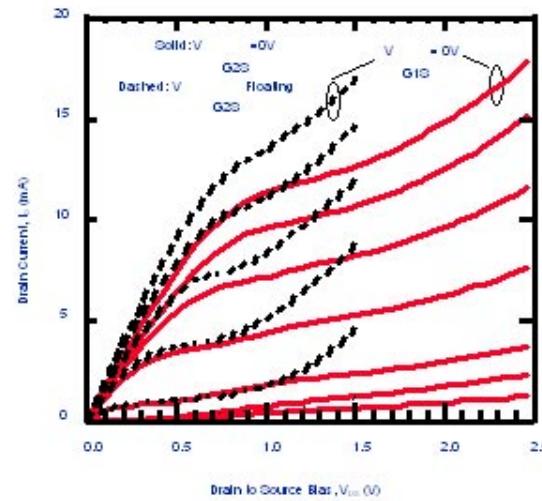


• Program Tasks

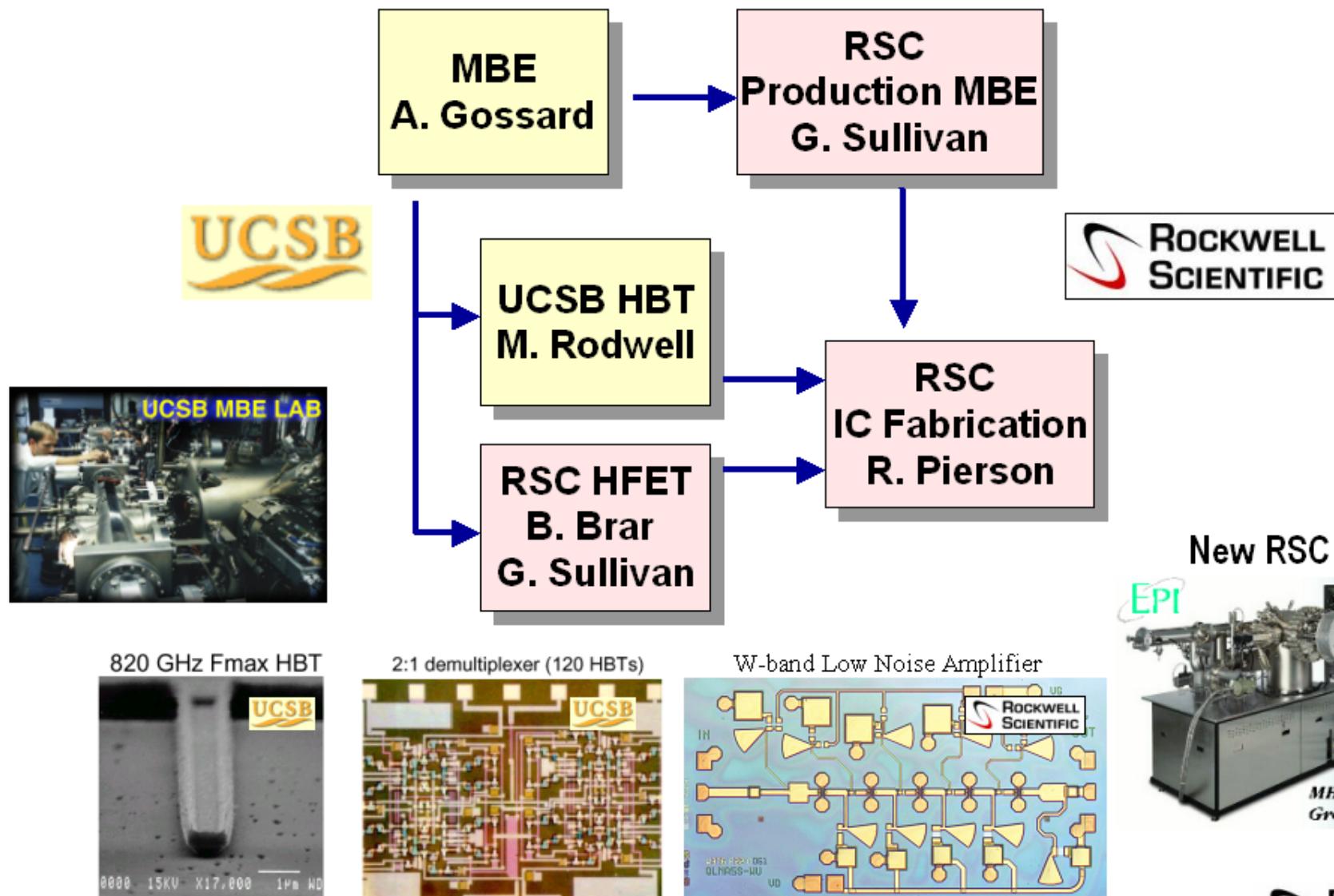
- Development of viable alternative substrate technology.
- Development of advanced ABCS nanometer-scale HEMT IC. Technology.
- Development of low V_{be} ABCS HBT IC Technology.
- Design and fabrication of mixed-signal/integrated circuits with unprecedented unloaded propagation delay (<4 pS) and power-delay product (<1 fJ).
- Incorporation into a manufacturable IC process.
- Development of complex prototypes for possible systems applications.

InAs-based HBT

Load Line for 2
levels of logic.

InAs-based HEMT

RSC & UCSB ABCS Team

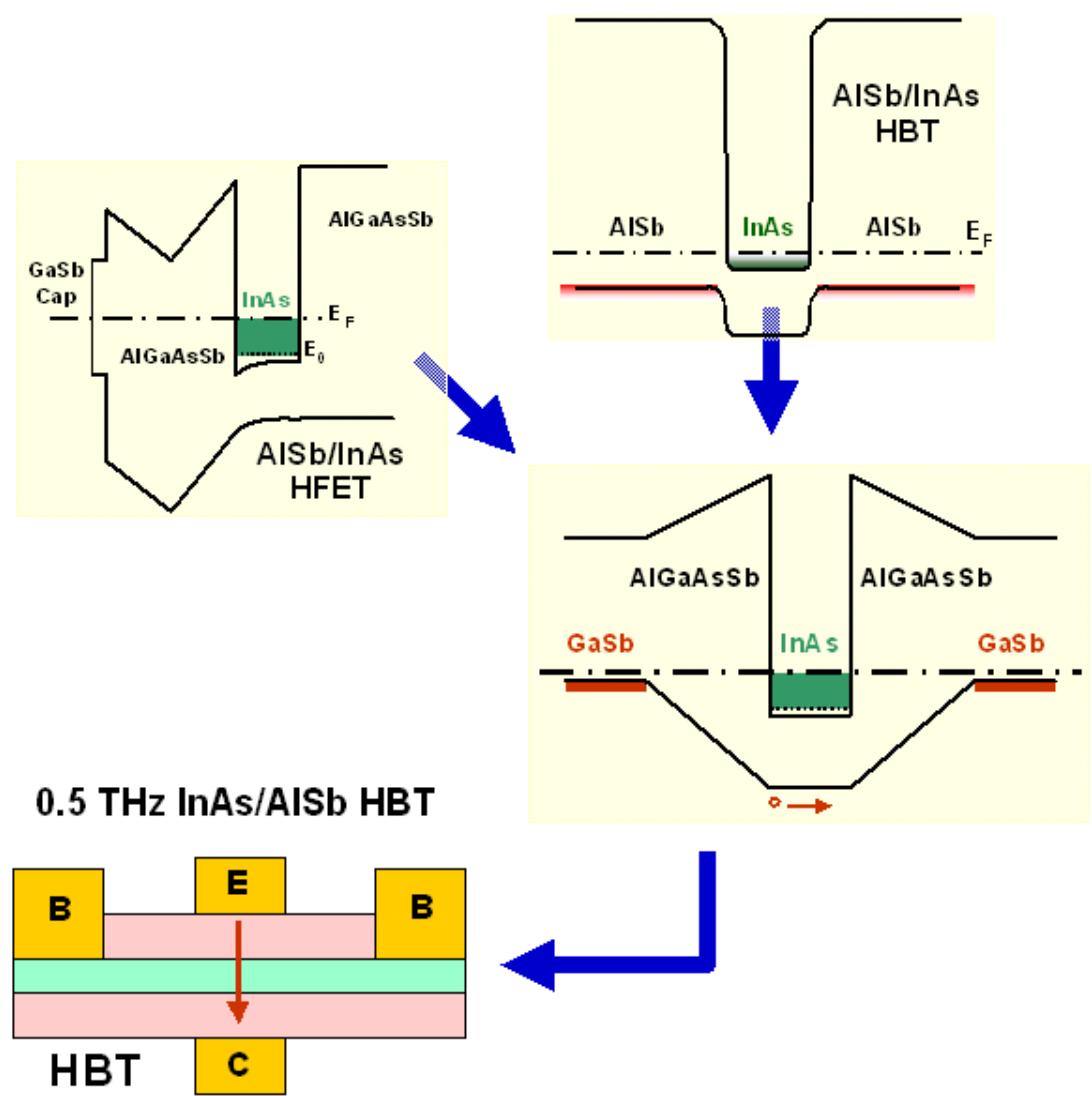


ROCKWELL
SCIENTIFIC

Transferred-Substrate Antimonide-Based Devices

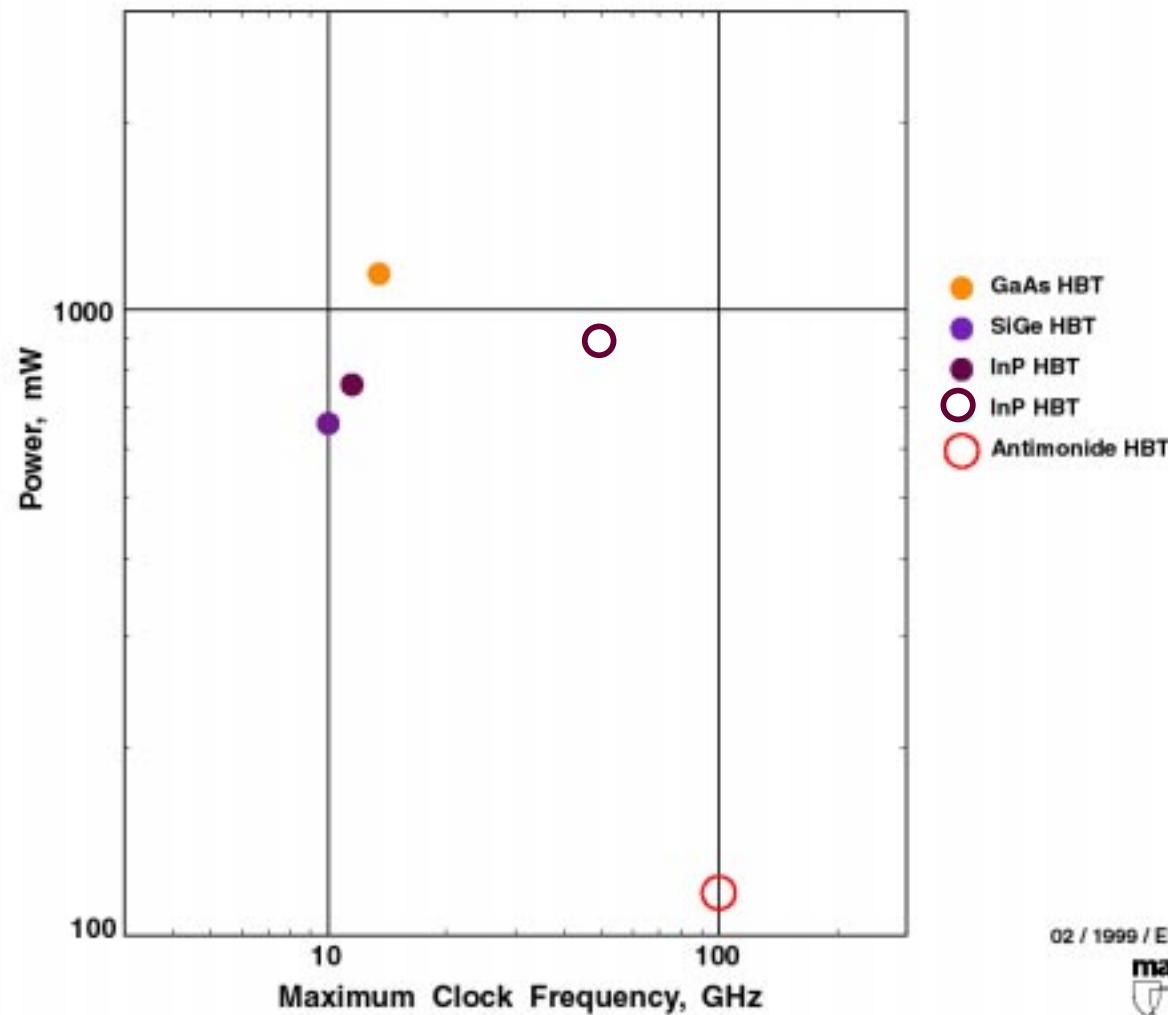
HFETs & HBTs for high-speed low-power circuits

- 0.6dB NF, 12dB gain, 2.4mW W-band LNAs
- 8-channel, 400mW, 80 Gbps MUX/DEMUX
- No Substrate Limitations
- Ultimate Scaling
- Possible HBT/HFET Circuits





Circuit Design: Improvement with Antimonide HBT



02 / 1999 / ESD / 16007



2:1 Mux/Demux HSPICE CML logic circuit simulation



**SYSTEM ENABLING CAPABILITIES OF ANTIMONIDE DEVICES: ANTIMONIDES OPEN UP
ENTIRELY NEW OPERATING REGIMES IN SPEED/POWER PERFORMANCES**
 (Numerical Values Based on HSPICE Simulations Conducted at
 Mayo Foundation Using Representative Analog and Digital Circuits)

APPLICATION	EXISTING TECHNOLOGY	UTILIZATION OF ANTIMONIDES																								
DIGITAL RADAR RECEIVER WITH DELTA-SIGMA ADC	<table border="0"> <tr> <td>LNA: InP E-HEMT 1 dB NF, 8 dB Gain</td> <td>24 mW</td> <td>LNA: InAs E-HEMT 0.6 dB NF, 12 dB Gain</td> <td>3.6 mW</td> </tr> <tr> <td>6 Bit 8 Gps ADC/DAC: InP HBT</td> <td>12.0 W</td> <td>6 Bit 16 Gps ADC/DAC: Ant. HBT</td> <td>2.4 W</td> </tr> <tr> <td>14 Bit Delta-Sigma Loop Filter (250 MHz Bandwidth)</td> <td>10.0 W</td> <td>14 Bit Delta-Sigma Loop Filter (500 MHz Bandwidth)</td> <td>10.0 W</td> </tr> <tr> <td>DEMUX: InP HBT 6:48</td> <td>15.0 W</td> <td>DEMUX: Ant. HBT 6:96</td> <td>1.3 W</td> </tr> <tr> <td>Digital: CMOS</td> <td>2.5 W</td> <td>Digital: CMOS</td> <td>5.0 W</td> </tr> <tr> <td>Total:</td> <td>42.0 W</td> <td><i>*Twice the Bandwidth, Less Than 1/2 the Power</i></td> <td>Total: 19.2 W</td> </tr> </table>	LNA: InP E-HEMT 1 dB NF, 8 dB Gain	24 mW	LNA: InAs E-HEMT 0.6 dB NF, 12 dB Gain	3.6 mW	6 Bit 8 Gps ADC/DAC: InP HBT	12.0 W	6 Bit 16 Gps ADC/DAC: Ant. HBT	2.4 W	14 Bit Delta-Sigma Loop Filter (250 MHz Bandwidth)	10.0 W	14 Bit Delta-Sigma Loop Filter (500 MHz Bandwidth)	10.0 W	DEMUX: InP HBT 6:48	15.0 W	DEMUX: Ant. HBT 6:96	1.3 W	Digital: CMOS	2.5 W	Digital: CMOS	5.0 W	Total:	42.0 W	<i>*Twice the Bandwidth, Less Than 1/2 the Power</i>	Total: 19.2 W	
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HIGH SPEED OPTICAL TRANSCEIVER LINK	<table border="0"> <tr> <td>Data Rate: 40 Gb/s</td> <td>Data Rate: 80 Gb/s</td> </tr> <tr> <td>Analog Components (TIA, PLL, AGC): InP HBT</td> <td>Analog Components (TIA, PLL, AGC): Antimonide HBT</td> </tr> <tr> <td>Laser Diode (InGaAs):</td> <td>Laser Diode (InGaAs):</td> </tr> <tr> <td>1st MUX/DEMUX: InP HBT 1:4</td> <td>1st MUX/DEMUX: Ant. HBT 1:8</td> </tr> <tr> <td>2nd MUX/DEMUX: SiGe HBT 4:32</td> <td>2nd MUX/DEMUX: SiGe HBT 8:64</td> </tr> <tr> <td>Total: 9.9 W</td> <td>Total: 9.9 W</td> </tr> </table>	Data Rate: 40 Gb/s	Data Rate: 80 Gb/s	Analog Components (TIA, PLL, AGC): InP HBT	Analog Components (TIA, PLL, AGC): Antimonide HBT	Laser Diode (InGaAs):	Laser Diode (InGaAs):	1st MUX/DEMUX: InP HBT 1:4	1st MUX/DEMUX: Ant. HBT 1:8	2nd MUX/DEMUX: SiGe HBT 4:32	2nd MUX/DEMUX: SiGe HBT 8:64	Total: 9.9 W	Total: 9.9 W													
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Total: 9.9 W	Total: 9.9 W																									
		<i>*Twice the Speed, Same Power</i>																								

**2-4x Improvements Are Extremely Important in Many Systems*

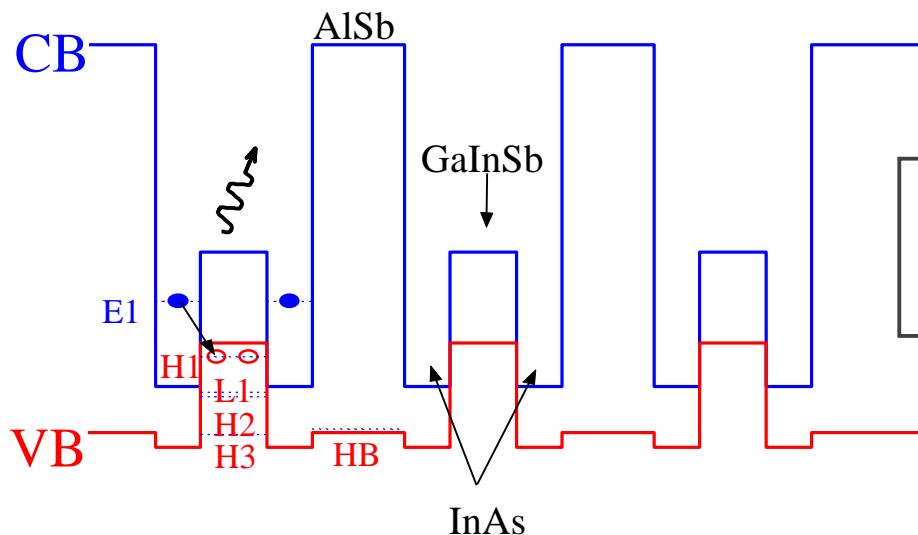
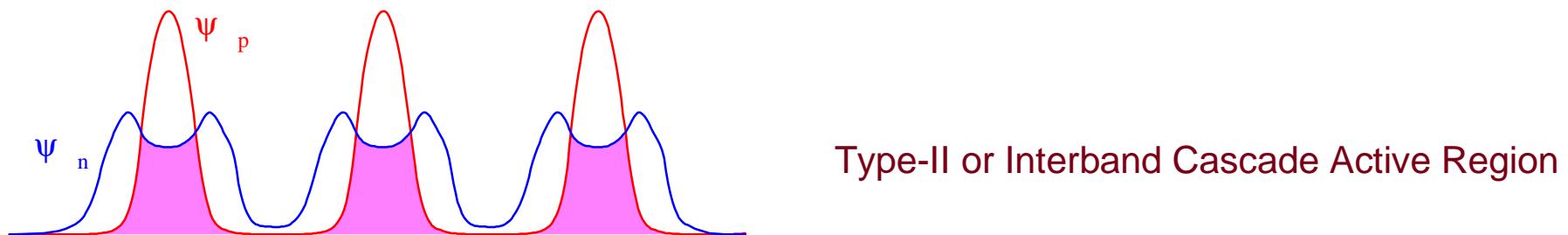
03 / 1999 / ESD / 16131




ABCS: IR Sources

Raising the Temperature: W Laser

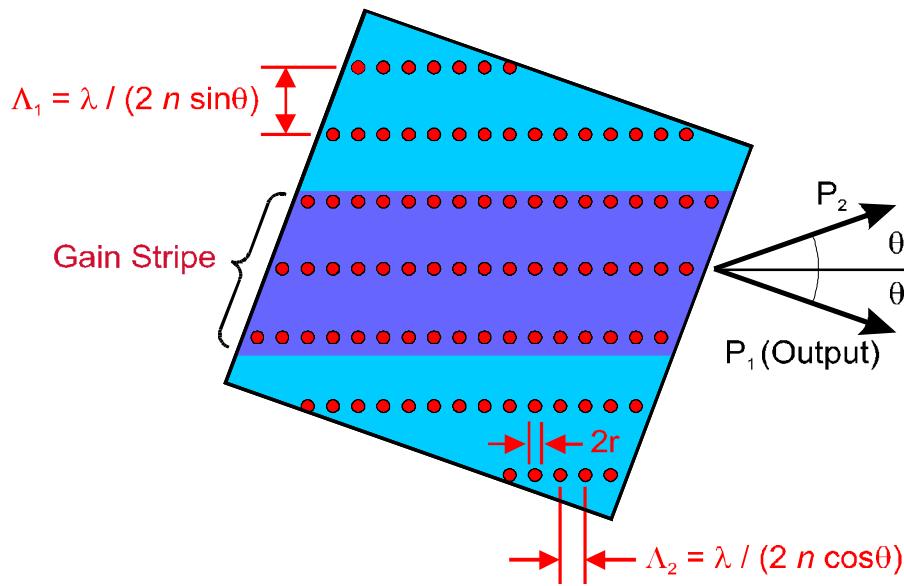
- ❖ Reduction of loss mechanisms
 - *10x demonstrated improvement*
- ❖ Wavefunction overlap with electrical confinement
 - e^- and h^+ in separate layers



Meyer et al. APL 67,757 (1995)



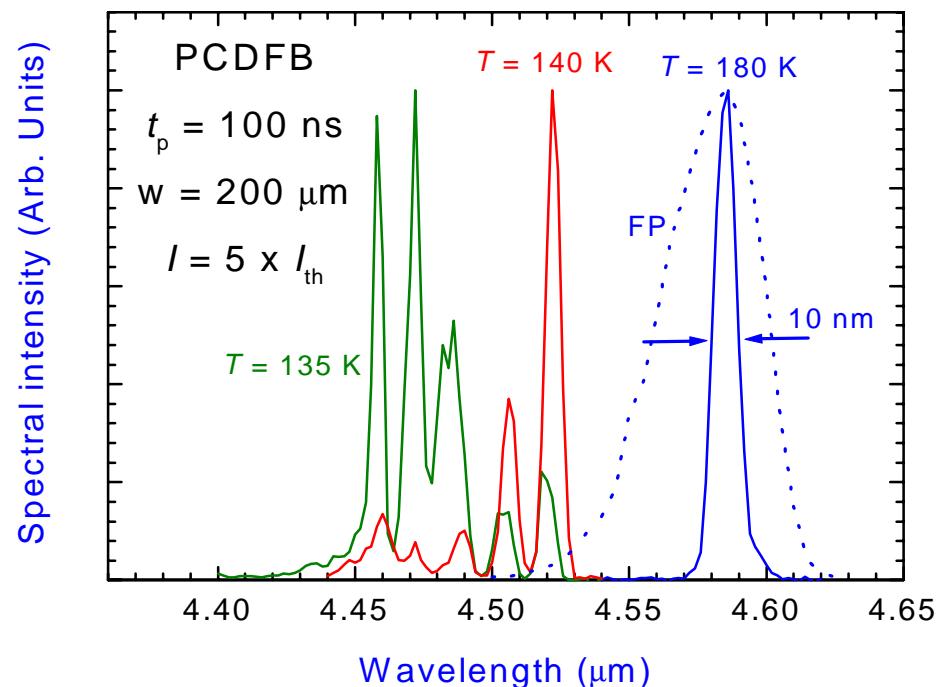
ABCS Photonic Crystal Distributed Feedback Laser (PCDFB)



Distinct from “photonic bandgap” lasers

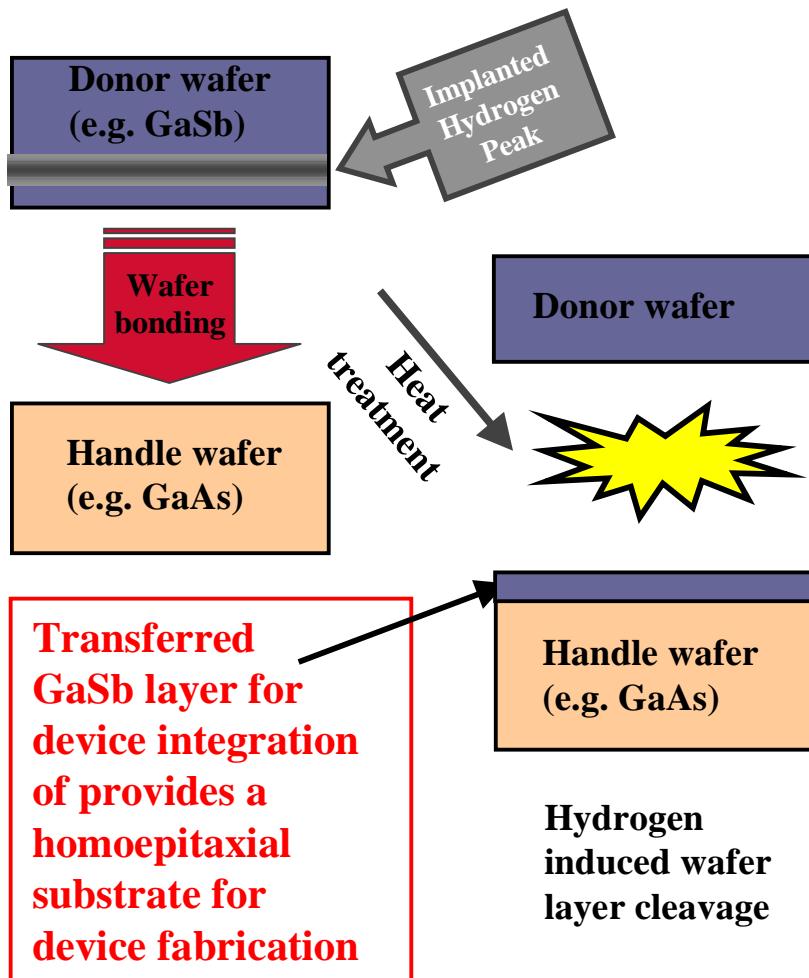
Vurgaftman et al., APL 78, 1466 (2001);
See also: S. Kalluri et al., ASLA, AWA6 (1999)

- 2D photonic crystal provides diffraction along two axes
 - Combines & enhances best features of DFB (spectral purity) & α -DFB (narrow divergence)

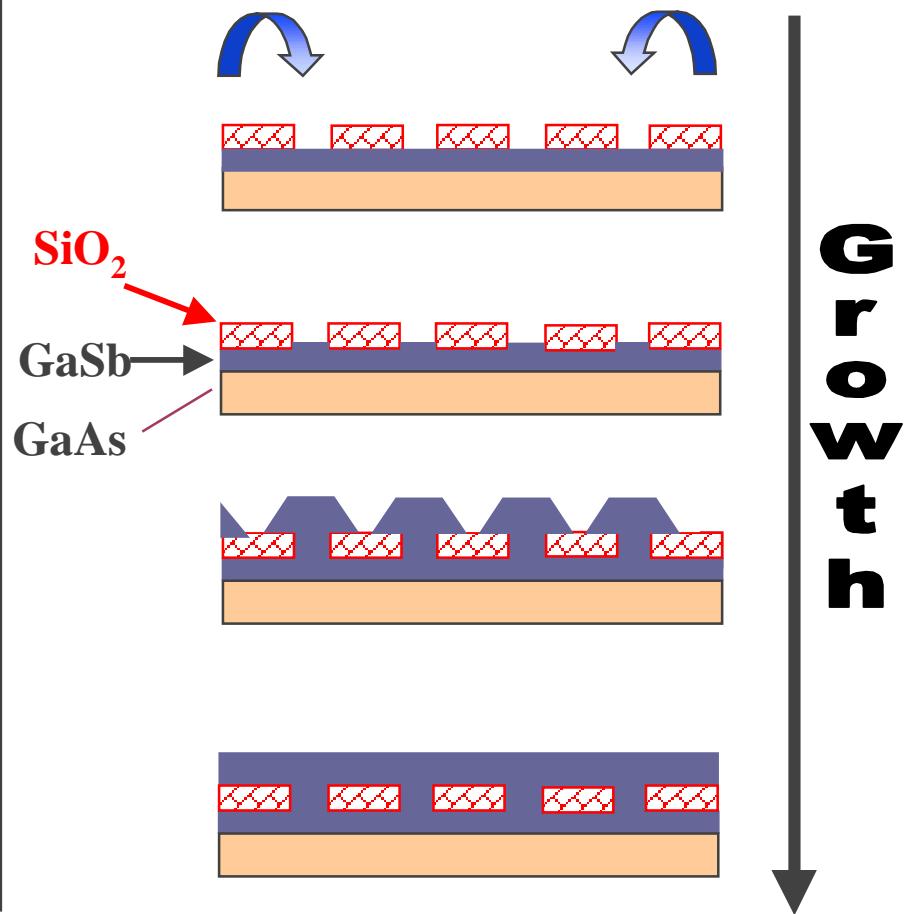


Key Challenge: Substrates

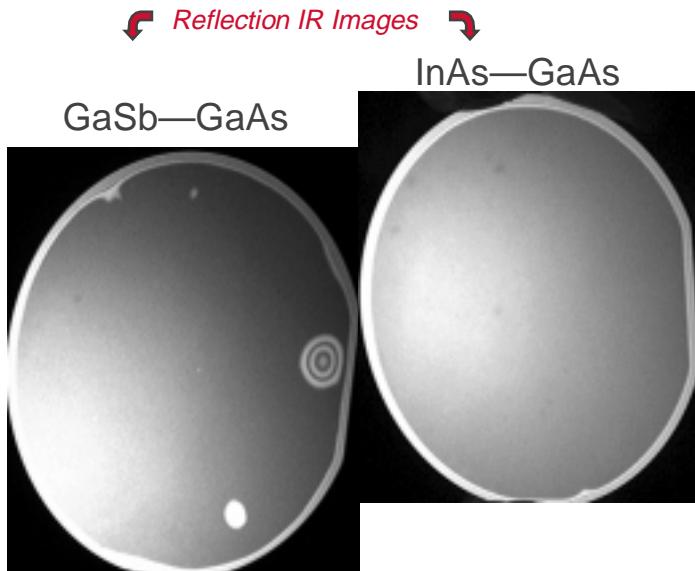
Ion-cut: Substrate formation for device integration



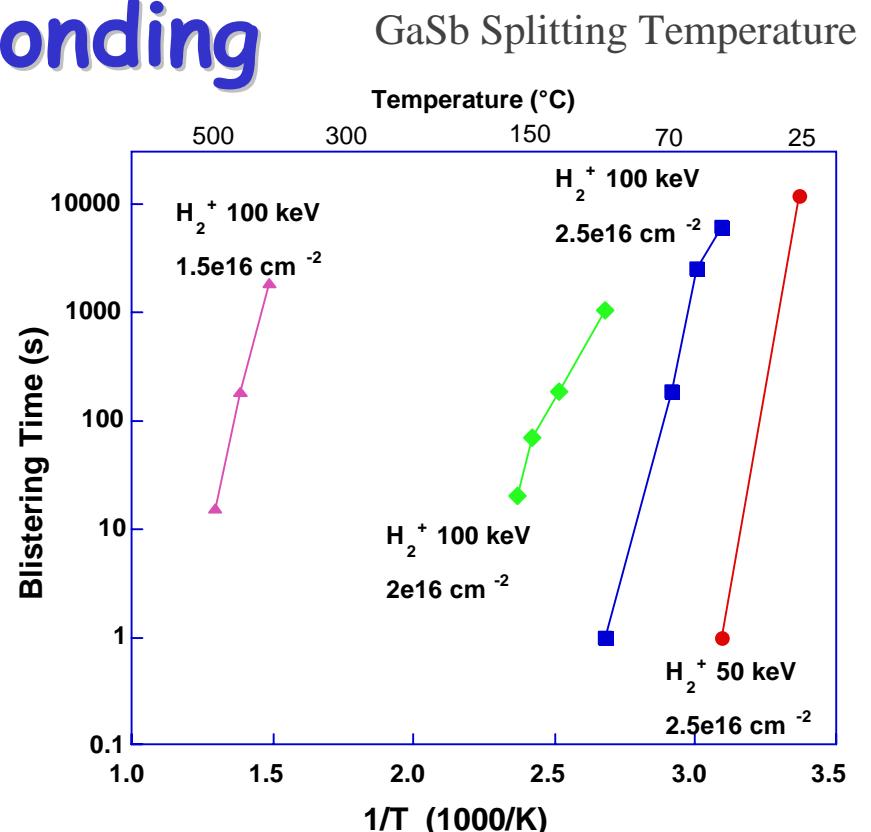
Lateral Epitaxial Overgrowth: Low defect density in overgrowth regions



Wafer Bonding



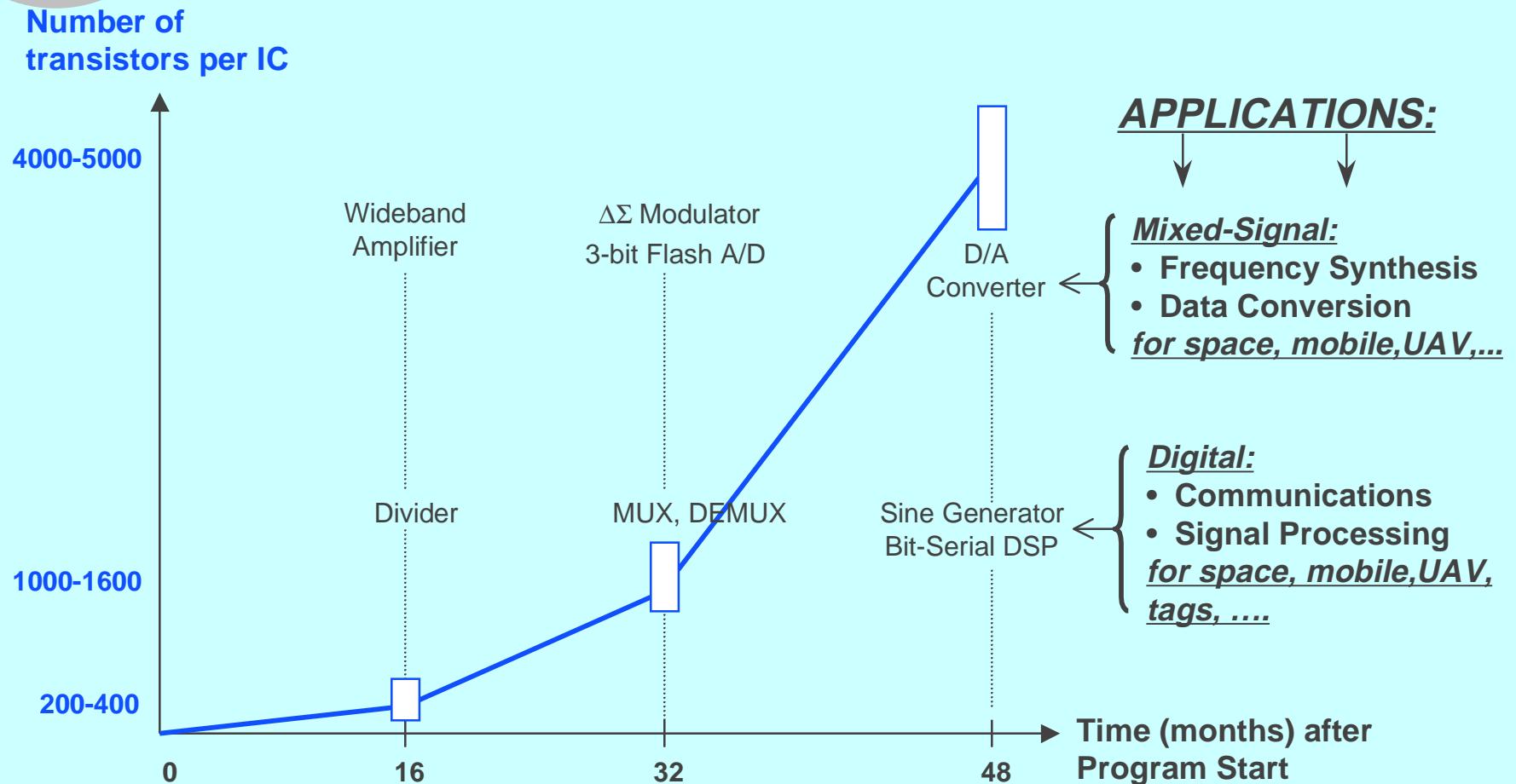
“As bonded” Images of 50 mm wafers



- ❖ GaSb and InAs have poor thermal conductivity, high carrier concentration and low mechanical strength
 - InAs and GaSb $\sim 0.01 \Omega \text{ cm}$ compared to $>10^7 \Omega \text{ cm}$ for SI GaAs
 - Diamond, poly-SiC or poly-AlN for μ wave and IR lasers
- ❖ Use wafer bonding for high performance substrates for 6.1\AA devices
 - SI GaAs substrates ($\sim 8\%$ lattice mismatch $\rightarrow 10^8 \text{ cm}^{-2}$ dislocations)

??

ABCS Integration Roadmap



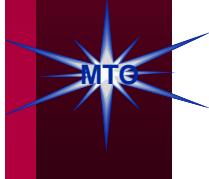


Micro Air Vehicles (MAV)

- ❖ Goal: Develop and demonstrate MAV less than 15 cm (in any dimension)
- ❖ Savings in power consumption important in the lighter MAVs
- ❖ High speed increases functionality in all cases (now using off-the-shelf Si-CMOS or SiGe products)
- ❖ Processing bottleneck: 1Mbps transmission pipeline and 1MIPS processors (only 2 frames/sec)

<i>MAV Requirements</i>		
<i>Specifications</i>	<i>Lutronix</i>	<i>Aerovironment</i>
Configuration	Rotary	Fixed wing
Dimensions	<15cm	<15cm
Mass	0.30kg	0.06kg
<i>Power Consumption (mW)</i>		
RF Communications	2,500	650
Processing	3,000	25
Sensors	100	<50
GPS	2,000	<400
Propulsion	72,400	5,000
Total Power	80W	6.2W

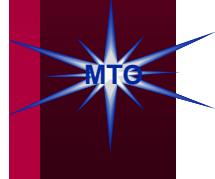
ABCS electronics will result in less power consumption and more functionality (high speed)





ABCS Technical Issues

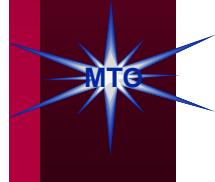
- ❖ Low voltage operation & noise margins
 - Innovative device design with bandgap engineering
 - III-V MOSFET
- ❖ Semi-insulating Substrates
 - Delaminating and rebonding
 - Metamorphic epitaxial growth
 - 'Novel' lattice matched substrates
- ❖ Circuit design
 - Third party assistance through MAYO
 - NEOCAD circuit demonstrations





Technical Challenges

- ❖ Substrates
 - semi-insulating for high frequency circuits
 - lower defect levels
 - minority carrier devices
- ❖ Integration
 - unique material and processing requirements to achieve combined functionality
 - 1000's of devices
 - HBT, HEMT + RTD for high frequency and low power
- ❖ Circuit design
 - overcome device-circuit technology gap
 - circuits can lag device performance by several generations
 - ensure viable noise margins for 0.5 V operation

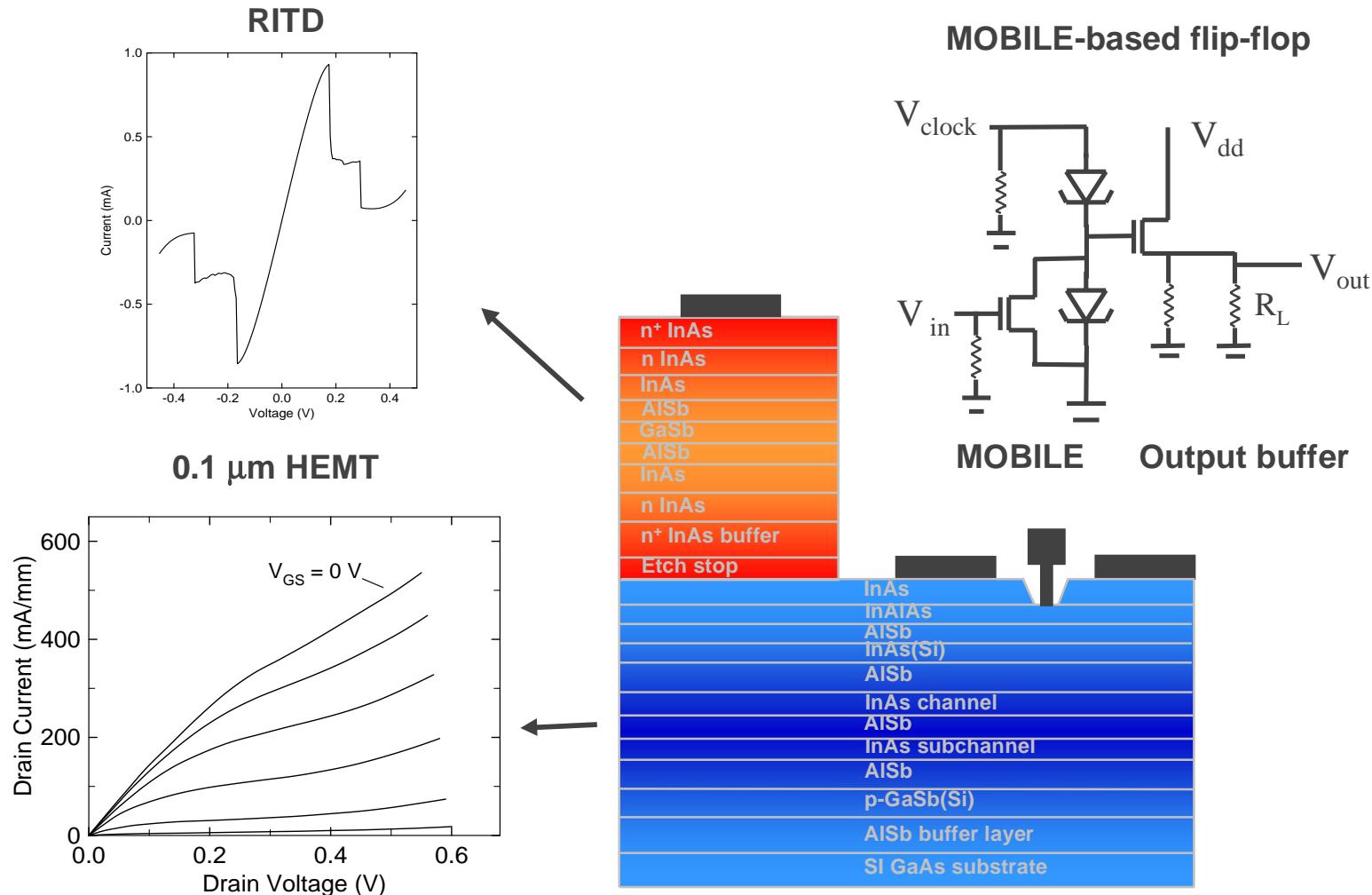


Material Comparison

	InAs	In _{0.53} Ga _{0.47} As	GaAs	InP
Electron Effective Mass (m_{Γ}^*/m_0)	0.023	0.041	0.067	0.077
Electron Mobility (cm ² /V-sec @ 300K, N _D =10 ¹⁷ cm ⁻³)	16000	7800	4600	2800
Γ- L Valley Separation (eV)	0.9	0.55	0.31	0.53
Electron Peak Velocity (10 ⁷ cm/sec)	4.0	2.7	2.2	2.5
Energy Bandgap (eV @ 300K)	0.36	0.72	1.42	1.35



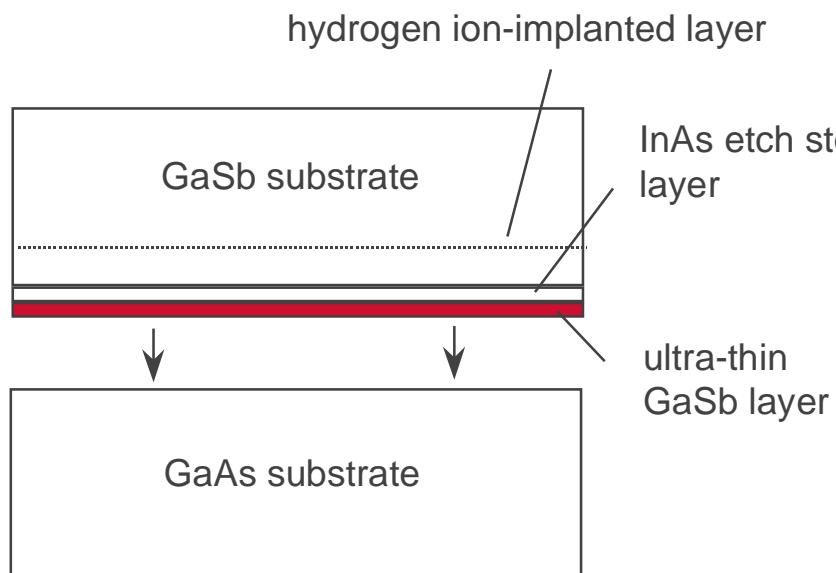
Sb-Based RITD/HEMT Logic Circuits



- Demonstrated material growth and fabrication technology required for integration
 - HEMT and RTD performance is comparable to that obtained on discrete devices

Making Ultra-Thin GaSb Layers on GaAs Substrate

“Ultra-Cut” Process

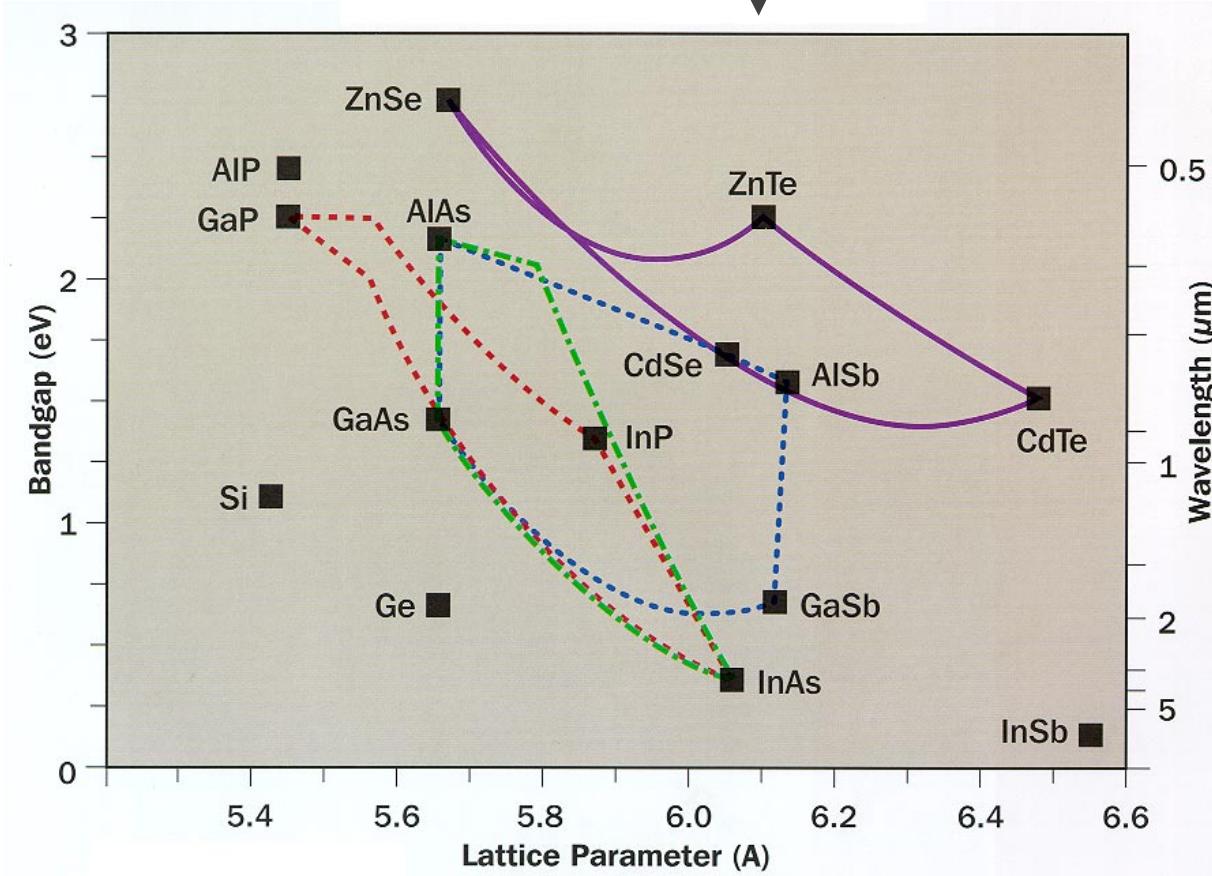


- ❖ Grow 25 nm InAs/GaSb layers on GaSb substrate.
- ❖ Implant hydrogen into GaSb substrate (peak is 100 nm below surface).
- ❖ Direct bond the GaSb surface to GaAs substrate.
- ❖ Heat wafer-bonded pair to split off GaSb substrate (Smart-Cut).
- ❖ Etch 100 nm of GaSb and stop at InAs layer.
- ❖ Etch InAs layer and stop at GaSb layer.
- ❖ Grow dislocation-free HEMT layers.



AlSb/InAs/GaSb Material System

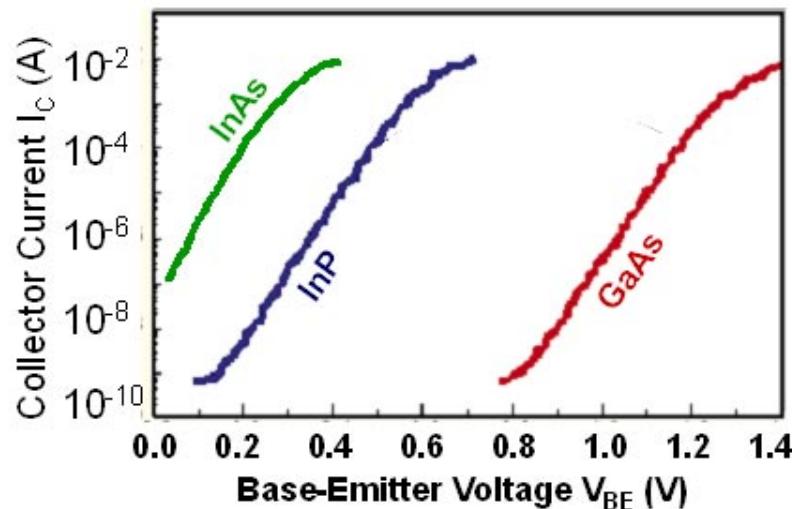
“6.1 Å” III-V Materials



MTG

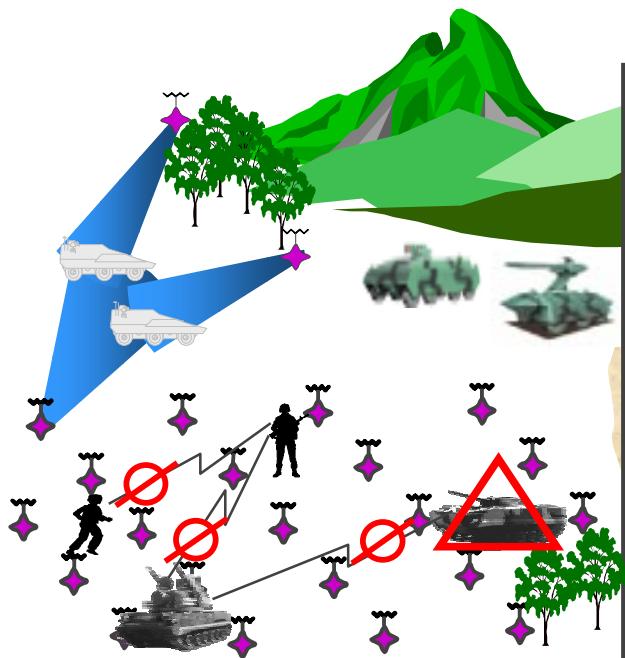
InAs HBT Technology

- ▶ A key use of InAs technology is for low power, high speed digital.
- ▶ Narrow bandgap materials have lower HBT Vbe turn-on voltage.
- ▶ Digital circuit designs have several Vbe stacks to the bias supply.
- ▶ The low InAs Vbe allows for either reduced power supply or increased gate functionality.

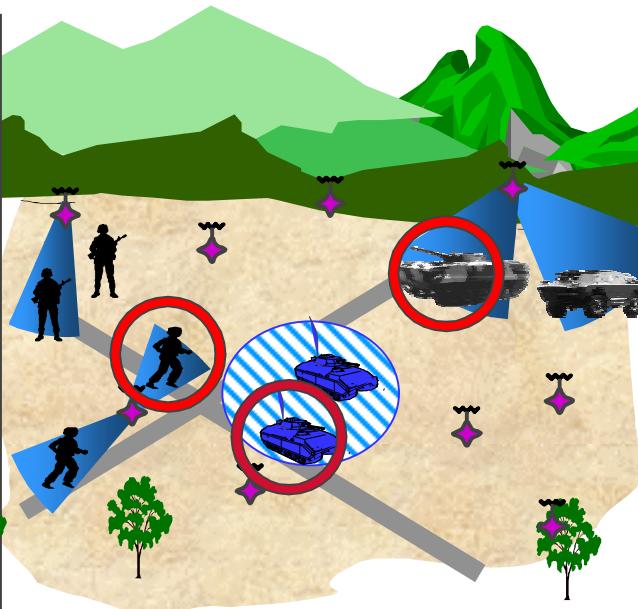


WolfPack : Operational Missions

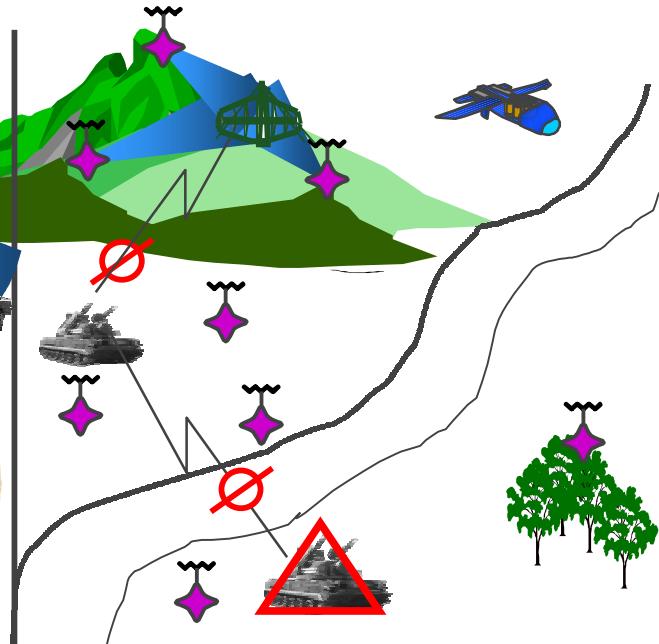
Electronic Attack



Electronic Protect



Distributed Suppression of Enemy Air Defenses



- Extend RF Situation Awareness / Response

- Selectively deny communications
- Precision target info
- Provide tactical deception

- Provide Safe Zone for Allied Operations

- Precision 3D location
 - Red / Blue
- Deny adversary comms
- Raise noise floor for cloaking of allied signals

- Enhance SEAD Lethal / Non-lethal Response

- Precision emplacement
- Suppress IADS
 - Communications
 - Radars
- Precision target Info



Movies: Can be effective.....



WolfPack: Concept.....

